

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/510,074	AOKI ET AL.	
Examiner		Art Unit		Page 1 of 1
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,400,929	06-2002	Ue et al.	455/69
	B	US-			
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

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